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XAS Data Processing

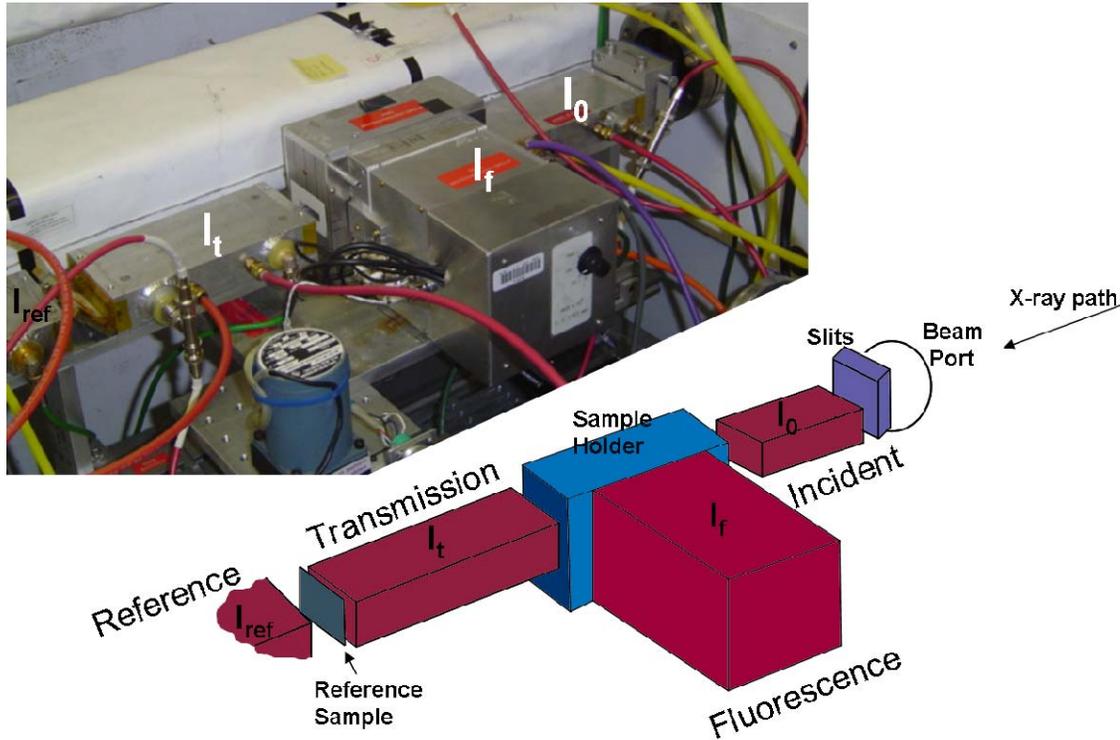
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Outline

- X-ray absorption signal
- Reference spectra
- Aligning and merging EXAFS signals
- Normalizing EXAFS spectra
- Conversion from energy to wavenumber
- Basics of Fourier transforms
- Background functions
- Fourier transform k-weights
- EXAFS Equation

X-ray Absorption Measurement

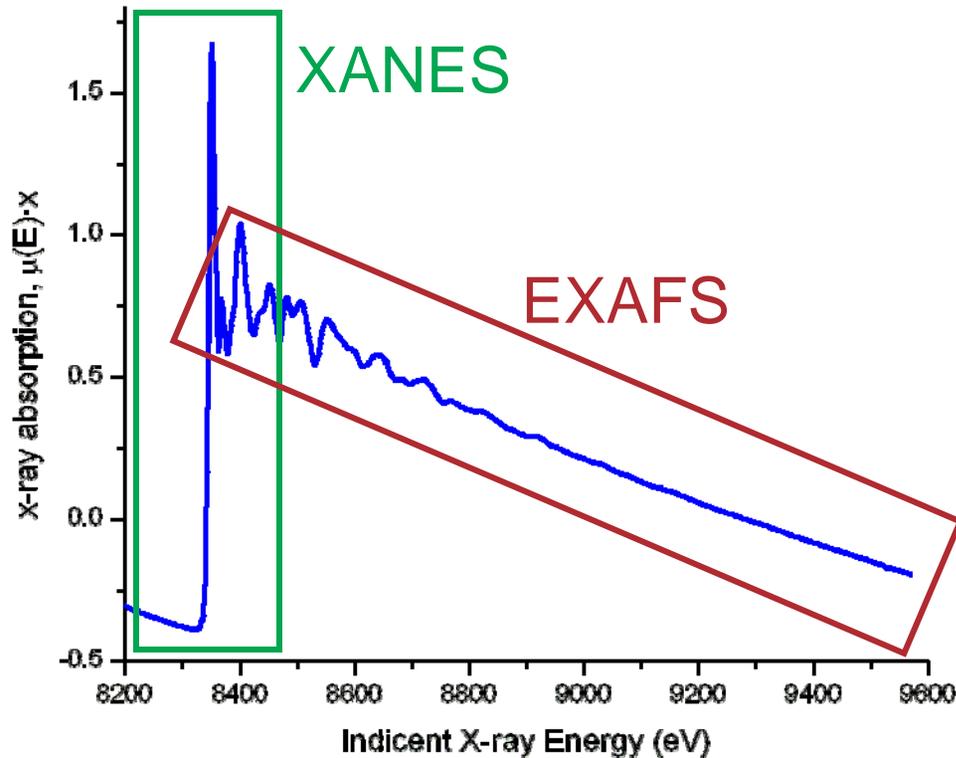


$$I_t = I_0 e^{-\mu \cdot x}$$

$$\mu \cdot x \propto \frac{I_f}{I_0}$$

The number of X-rays transmitted (I_t) through a sample is given the intensity of X-rays impinging on the sample (I_0) decreased exponentially by the thickness of the sample (x) and the absorption coefficient of the sample (μ)

X-ray Absorption Cross Section



Transmission Signal

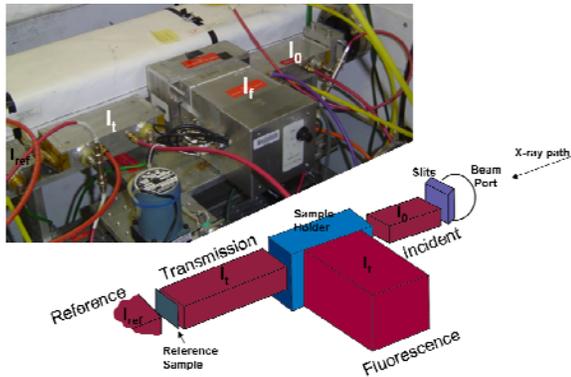
$$\mu \cdot x = \ln \left(\frac{I_0}{I_t} \right)$$

Fluorescence Signal

$$\mu \cdot x \propto \frac{I_f}{I_0}$$

- XAS: X-ray Absorption Spectroscopy
 - XANES: X-ray Absorption Near Edge Structure
 - EXAFS: Extended X-ray Absorption Fine Structure

Reference Spectra



Reference Placed in beam behind sample

$$\mu \cdot x = \ln \left(\frac{I_t}{I_{ref}} \right)$$

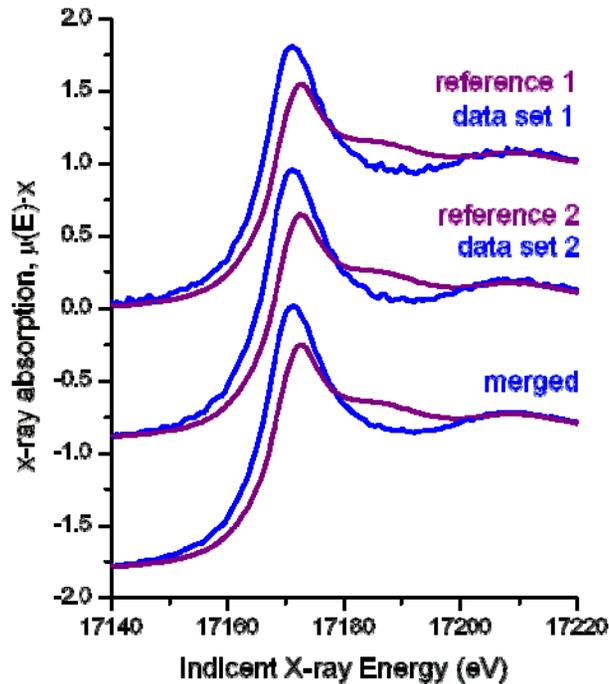
Reference placed beside beam¹

$$\mu \cdot x = \ln \left(\frac{I_0}{I_{ref}} \right)$$

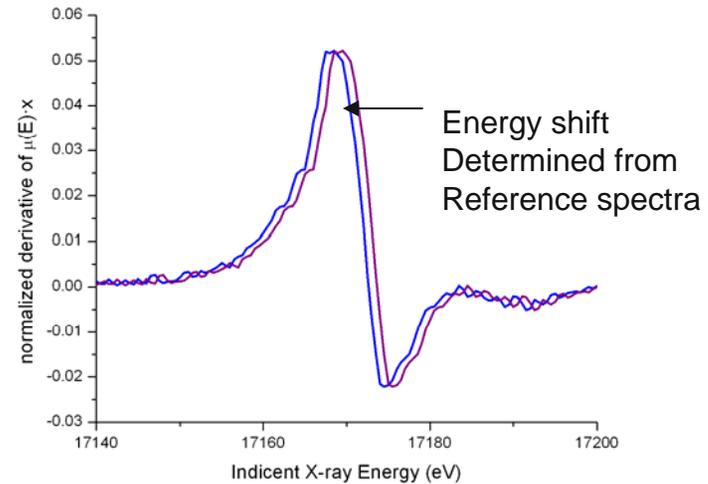
- X-ray absorption spectra should be checked for alignment before the spectra are averaged.
- A reference spectra can be collected with each sample spectra for this purpose.
 - Reference place behind transmission ionization chamber
 - Reference placed beside x-ray beam with a pin diode detector (for samples that do not transmit x-rays)
- The reference spectra are then shifted in energy so that their absorption edges are aligned and the shift is applied to the corresponding sample spectrum

¹Cross J. O. and Frenkel A. I. (1998) Use of scattered radiation for absolute energy calibration. *Rev. Sci. Instrum.* **70**, 38-40.

Aligning and Averaging Spectra

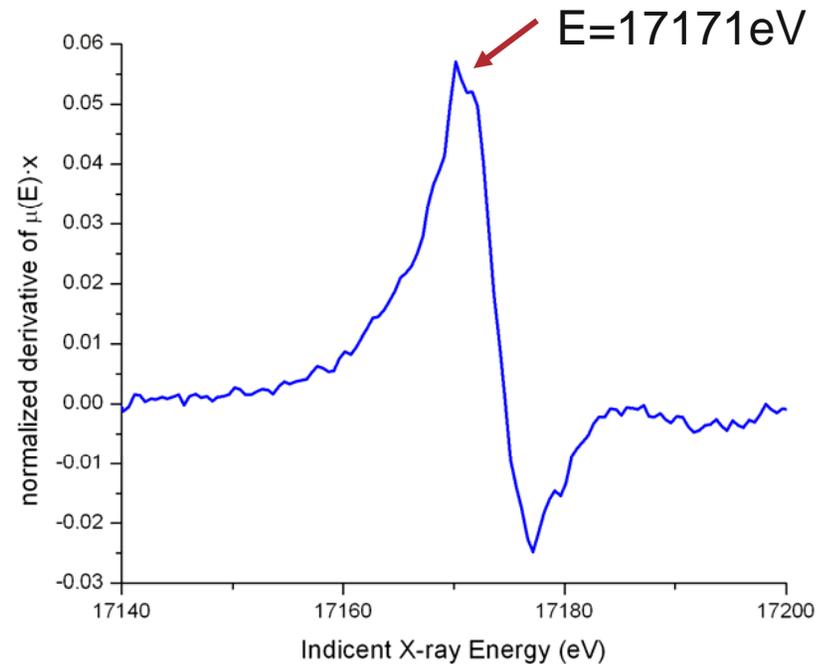
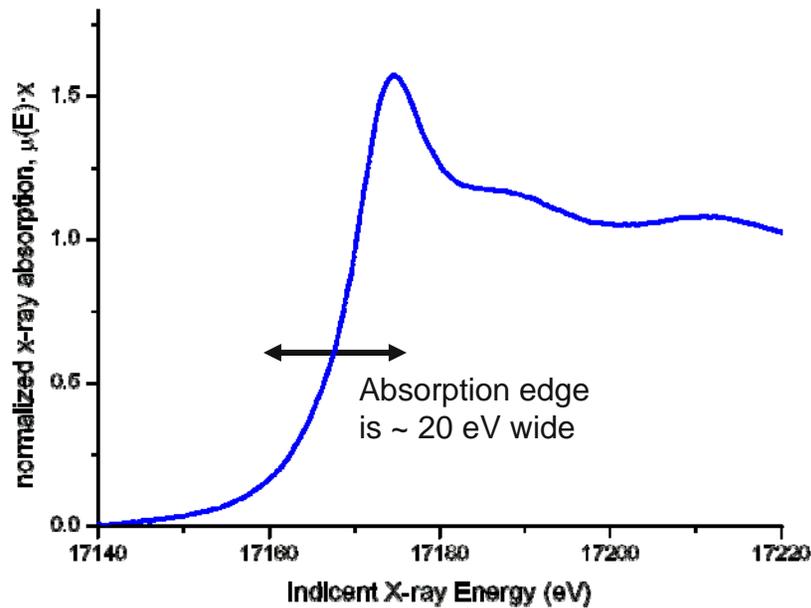


Derivative of Reference Spectra Edge



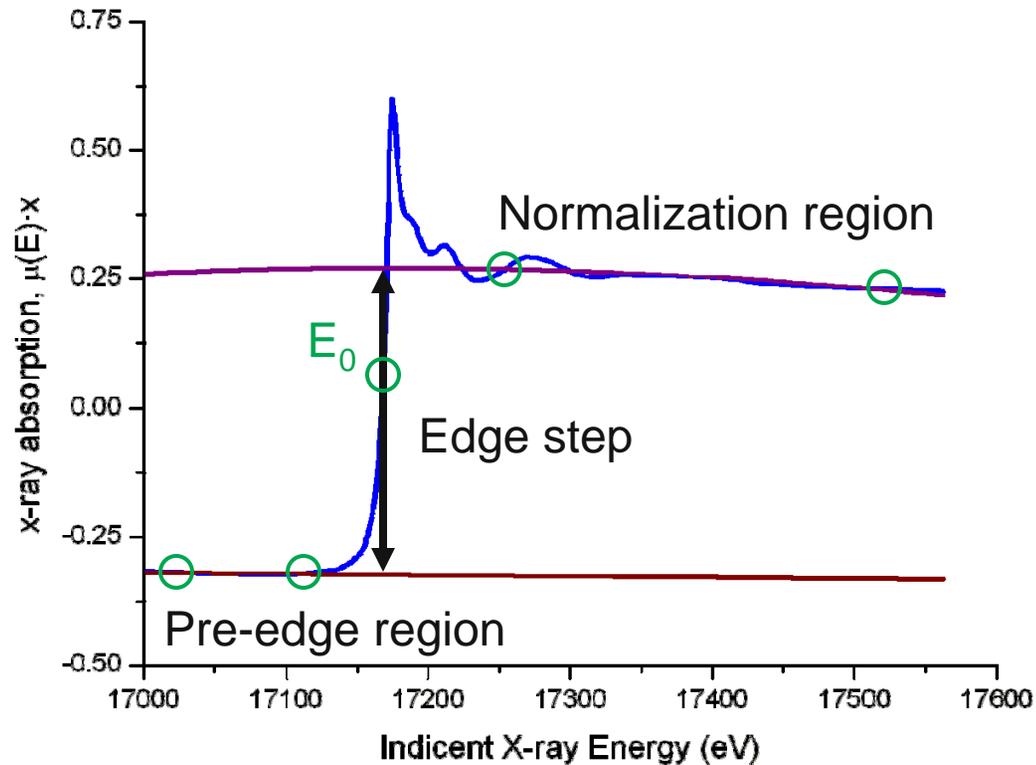
- Procedure
 - Reference spectrum 2 is aligned to reference spectrum 1 using derivative of edge
 - Data set 2 and reference 2 are shifted by the amount determined.
 - Data sets 1 and 2 are merged.
- It is good practice to align all the spectra to the same reference spectra for a given project.
- Data are often averaged as absorption spectra

Edge Energy



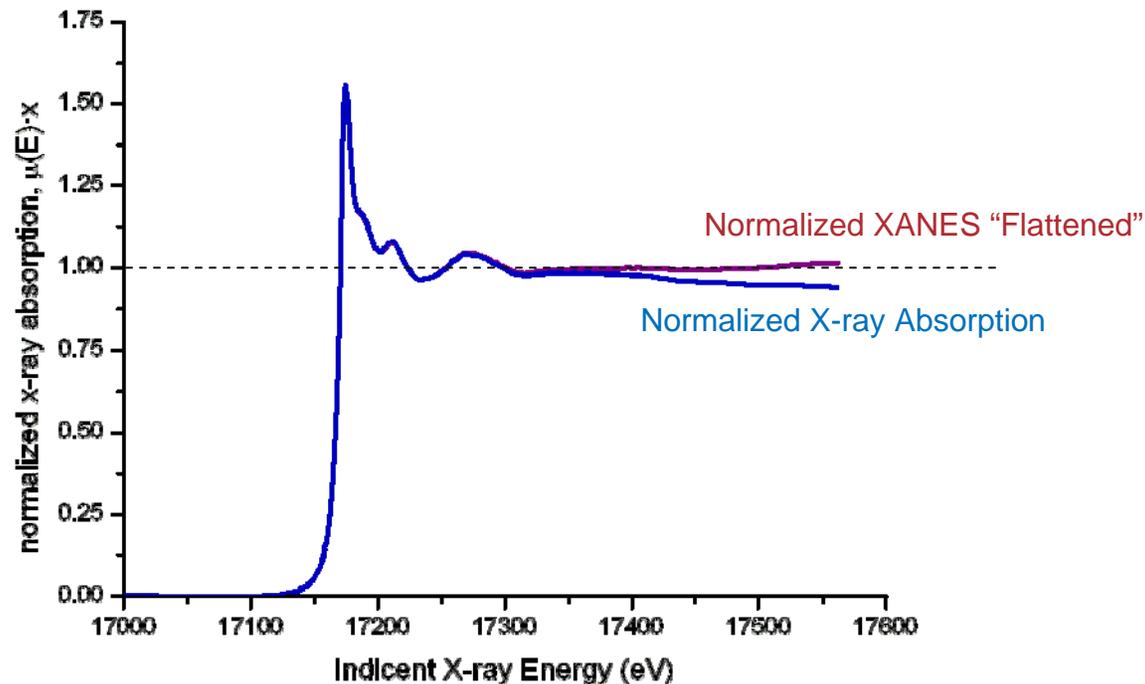
- The U L_{III}-edge absorption energy for U is defined as 17166 eV.
- The measured absorption edge is broad covering many eV.
- The first derivative of the edge for U(VI) is by convention set to 17171 eV and is useful for XANES comparisons.
- For EXAFS analysis E_0 (the edge energy) is used to defined $k = 0 \text{ \AA}^{-1}$ and is used to align the measured spectra to theoretical calculations.

Normalized X-ray Absorption Spectra



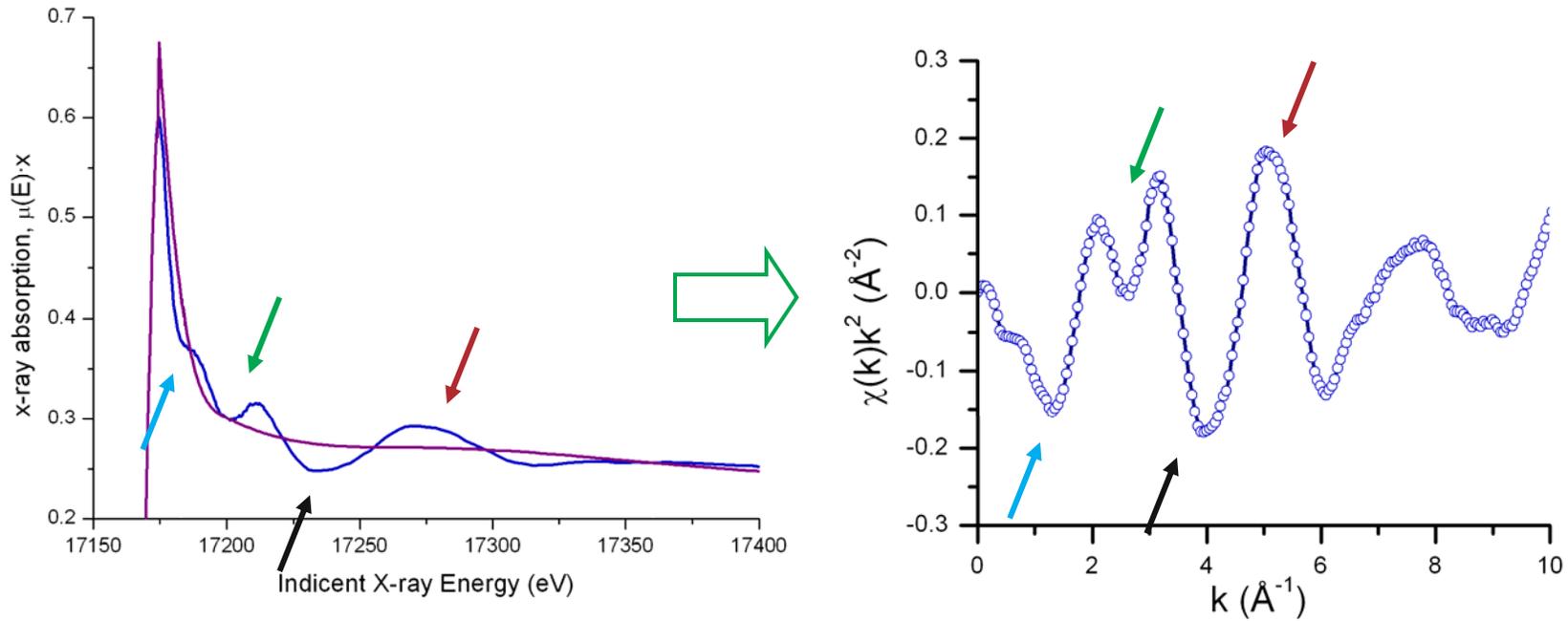
- Pre-edge line 200 to 50 eV before the edge
- Normalization line 100 to ~400 eV after the edge
- Edge step the change in the absorption coefficient at the edge
 - Evaluated by taking the difference of the pre-edge and normalization lines at E_0

Normalized X-ray Absorption Spectra



- Normalized X-ray Absorption Spectra is calculated by subtracting the pre-edge line from the entire spectra and dividing the entire spectra by the absorption edge step
- Athena has an extra feature used to flatten the absorption spectra above the edge, which can be helpful for comparing XANES spectra from different detectors.

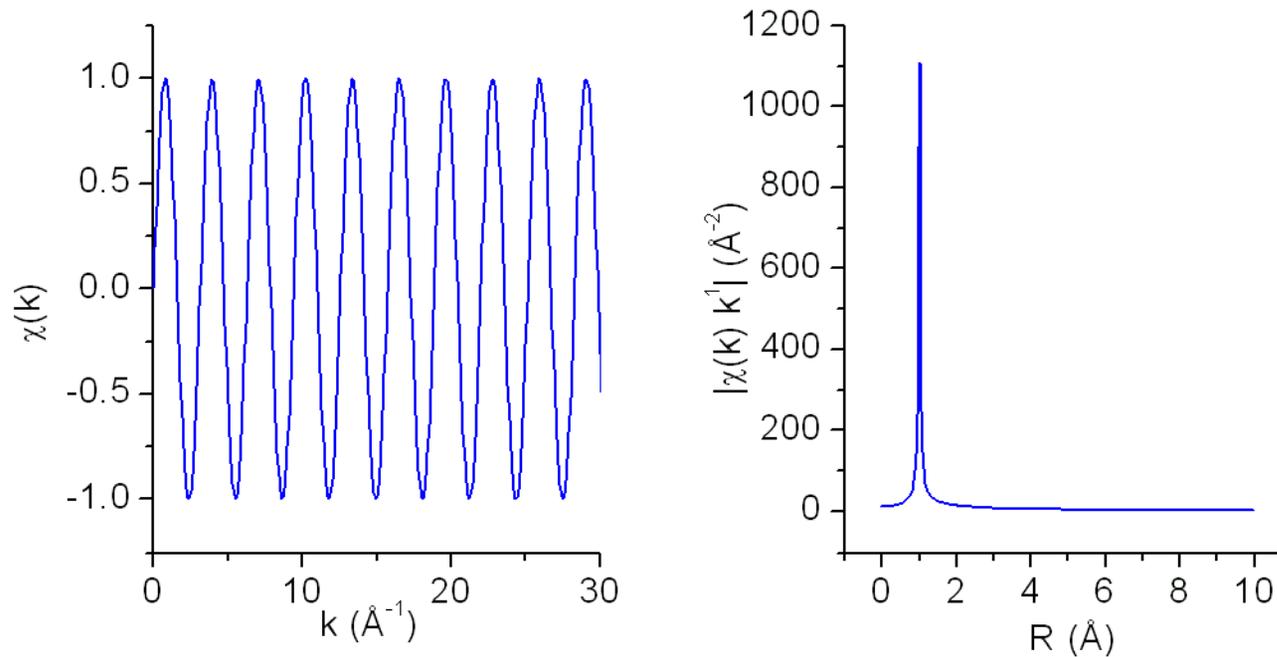
Conversion from Energy to Wavenumber



$$k^2 = \frac{2m_e (E - E_0 + \Delta E_0)}{\hbar^2}$$

Mass of electron $\rightarrow m_e$
 Energy above edge $\rightarrow E - E_0$
 Energy shift to align data to theory $\rightarrow \Delta E_0$
 wavenumber $\rightarrow k$
 Planck's constant $\rightarrow \hbar$

Fourier Transforms

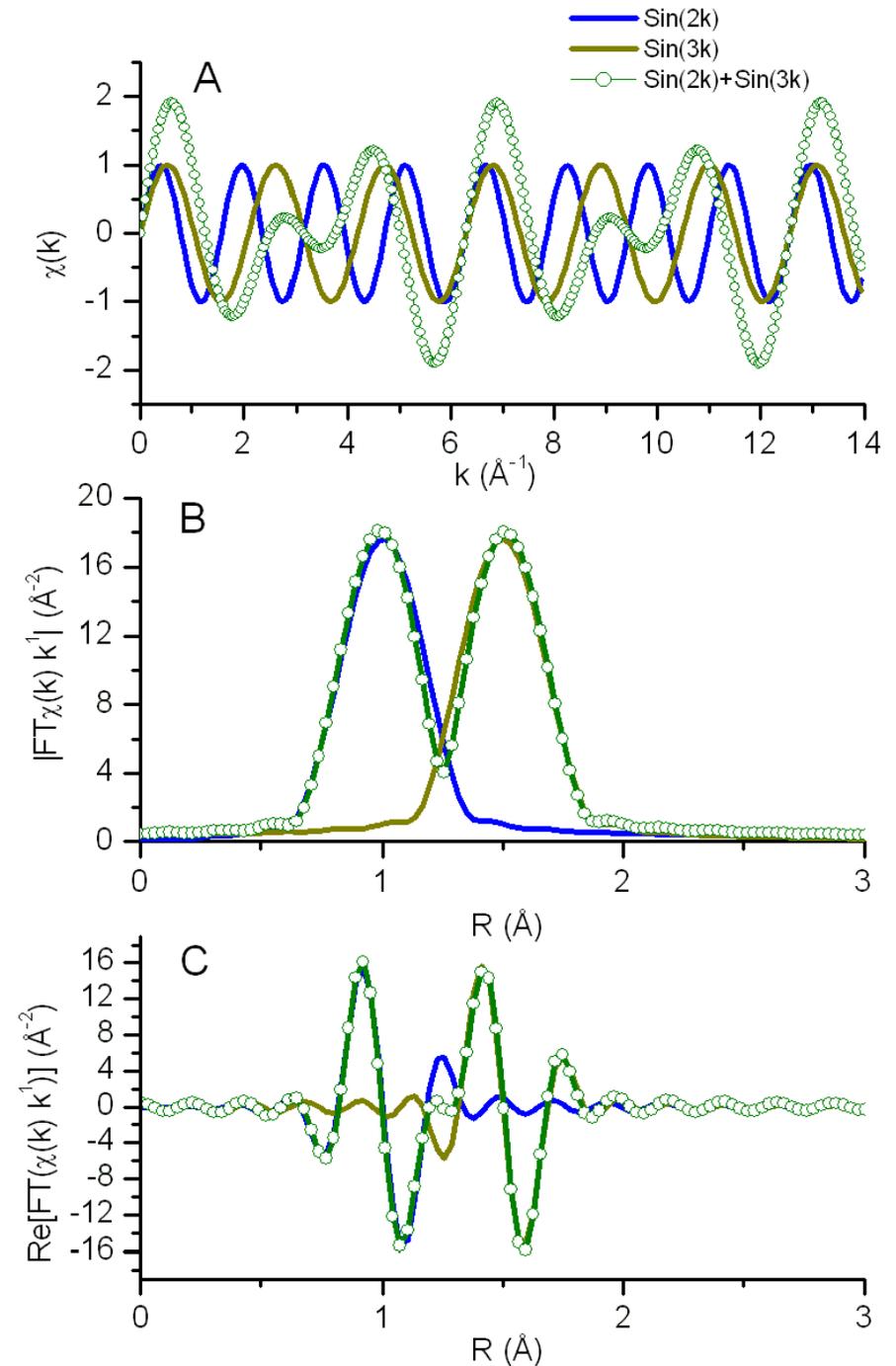


- Fourier transform of an infinite sine wave with a single phase of $2k$ is a delta function at $R = 1$ \AA .
- Signal that is de-localized in k -space is localized in R -space
- FT is a frequency filter

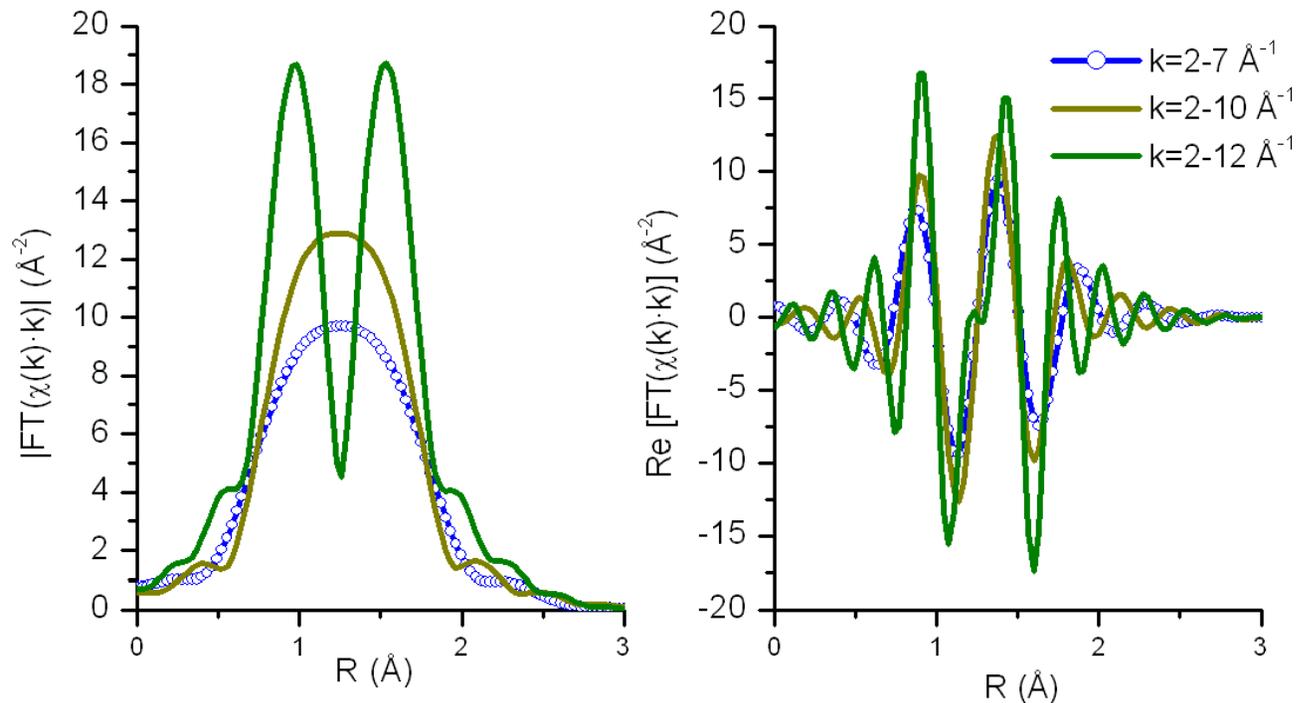
FT of two phase sine wave

- The Fourier transform of finite data range is a broad peak rather than a delta function
- The real part of the FT is a sum of the components of the FT of each sine wave
- The information content of a FT signal is given by Nyquist theorem

$$N_{IP} = \frac{2}{\pi} \cdot \Delta k \cdot \Delta R + 1$$



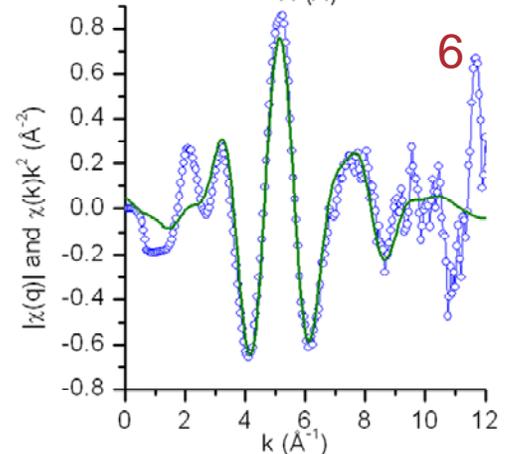
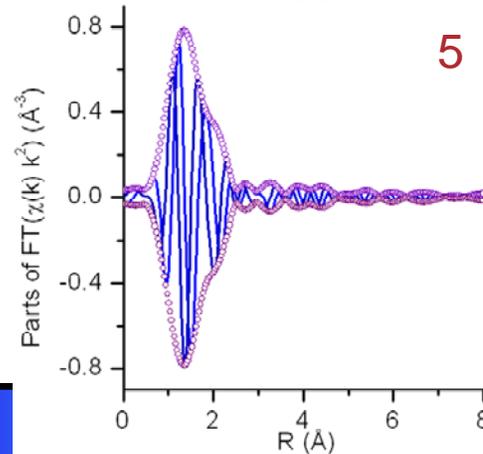
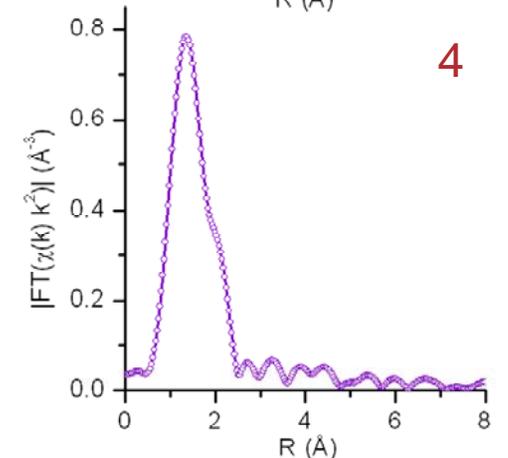
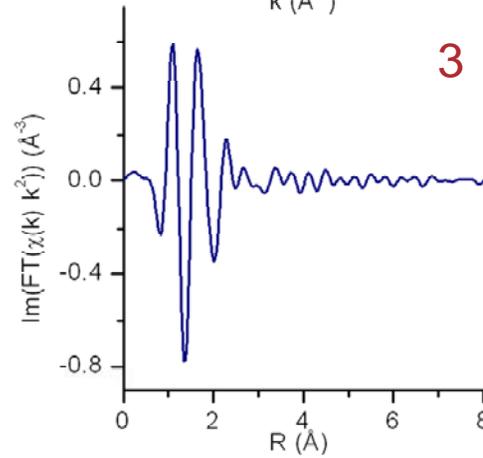
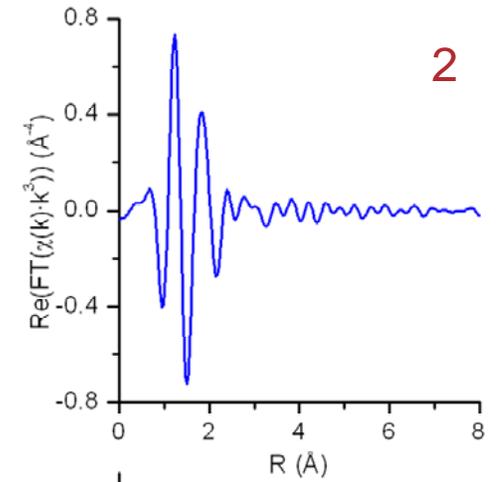
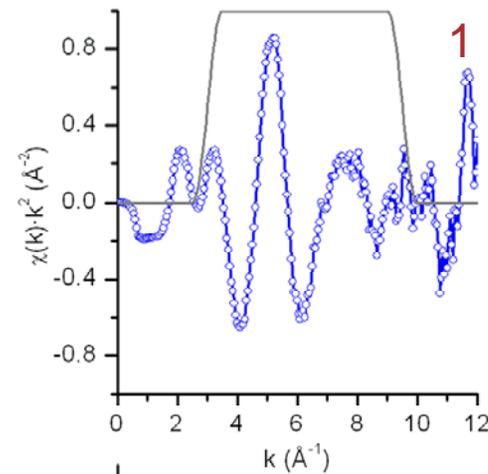
Information Content in the Fourier Transform



- Increasing the k-range included in the Fourier transform increases the information contained in the Fourier transformed signal
- All signals are included in the FT from $k=0$ and their content is carried to the FT signal
- The resolution given in these signals is $R = 0.3 \text{ \AA}$, 0.2 \AA , and 0.15 \AA , hence the signal separated by 1 \AA can be resolved even with the lowest k-range

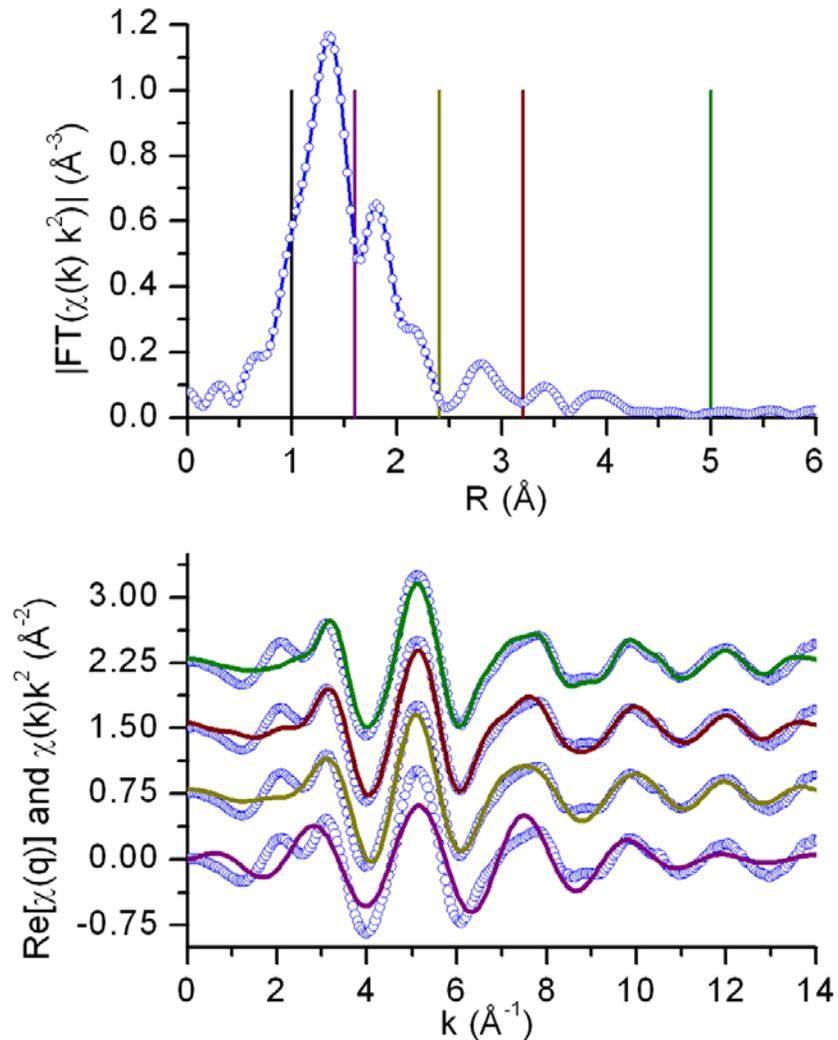
Parts of Fourier Transform

- 1: EXAFS spectra and window function
 - 2: Real part of FT
 - 3: Imaginary part of FT
 - 4: Magnitude of FT
 - 5: Real, imaginary, magnitude and inverse of magnitude of FT
 - 6: EXAFS spectra and back Fourier transformed spectra
- The real and imaginary parts of the Fourier transform contain more information than the magnitude of the FT.



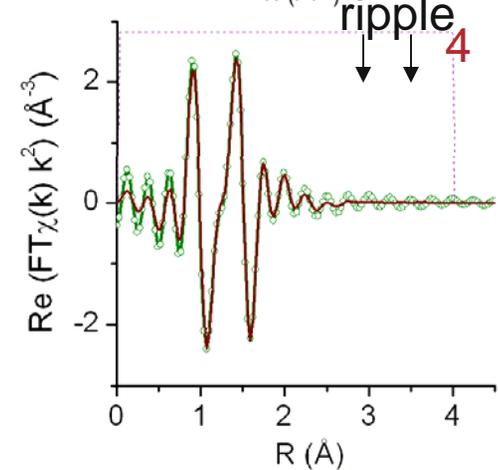
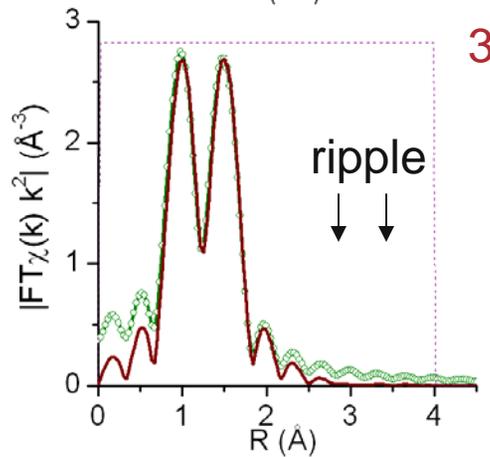
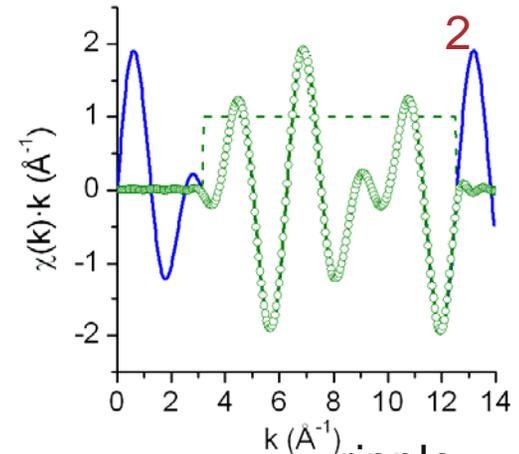
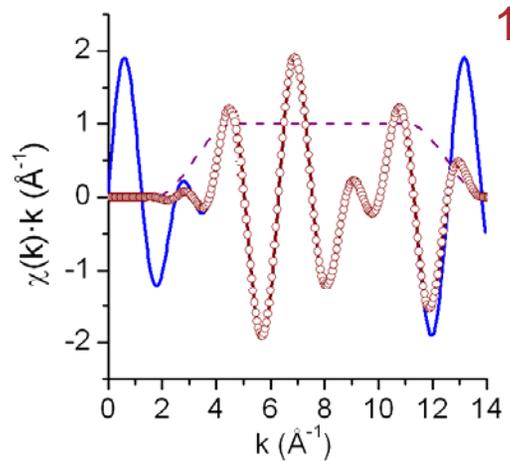
Back Fourier Transform

- The Back Fourier transform contains the information within the R-range.
- Used to compare the signal content within an R-range to the original EXAFS signal
- Longer phase signals are Fourier transformed to peaks at lower R values



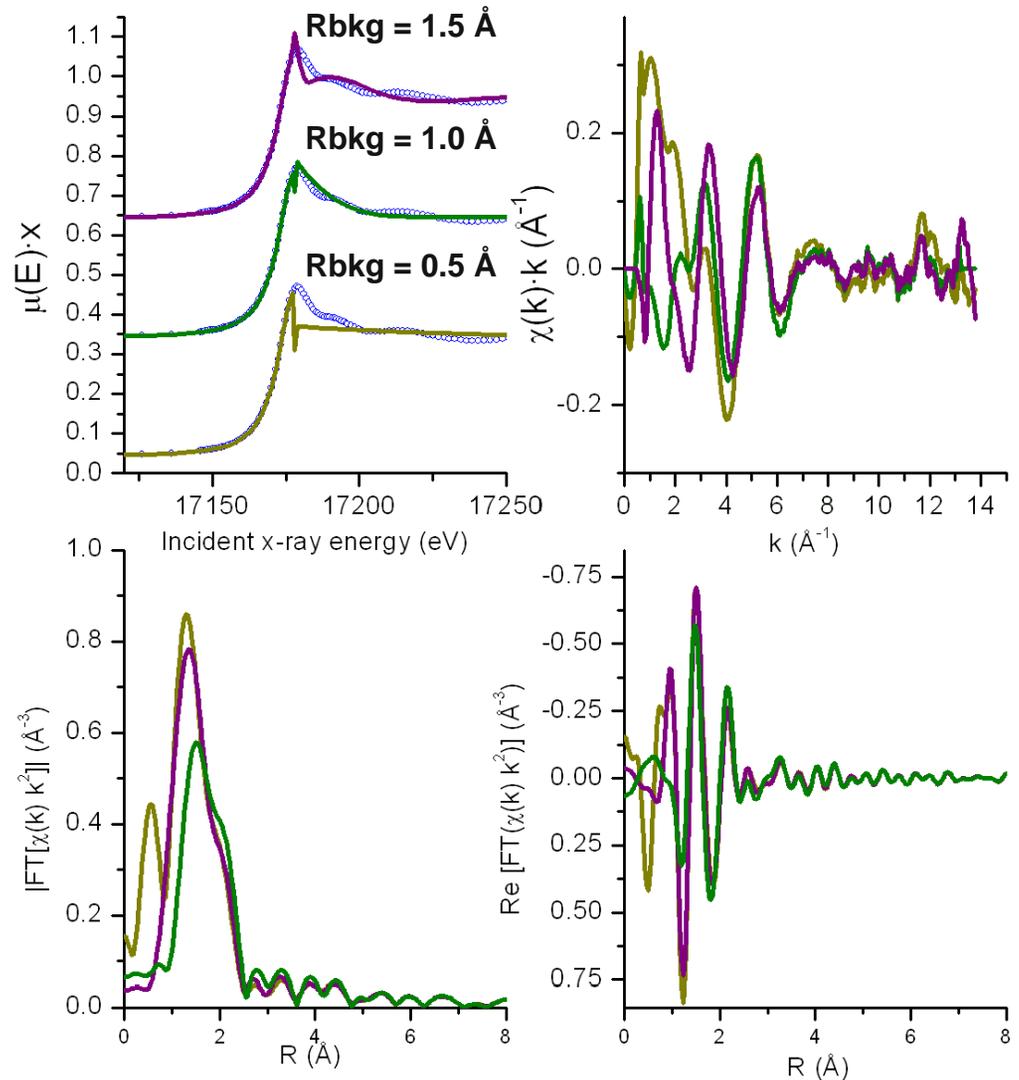
Fourier Transform Ripple

- Same data in blue is shown in 1 and 2.
- FT window is **broad** in 1 and **sharp** in 2
- Magnitude and real part of FT is shown in 3 and 4.
- Sharp window results in a FT ripple
- Back Fourier transformed spectra are shown in 1 and 2 illustrating the abrupt change in the green spectrum

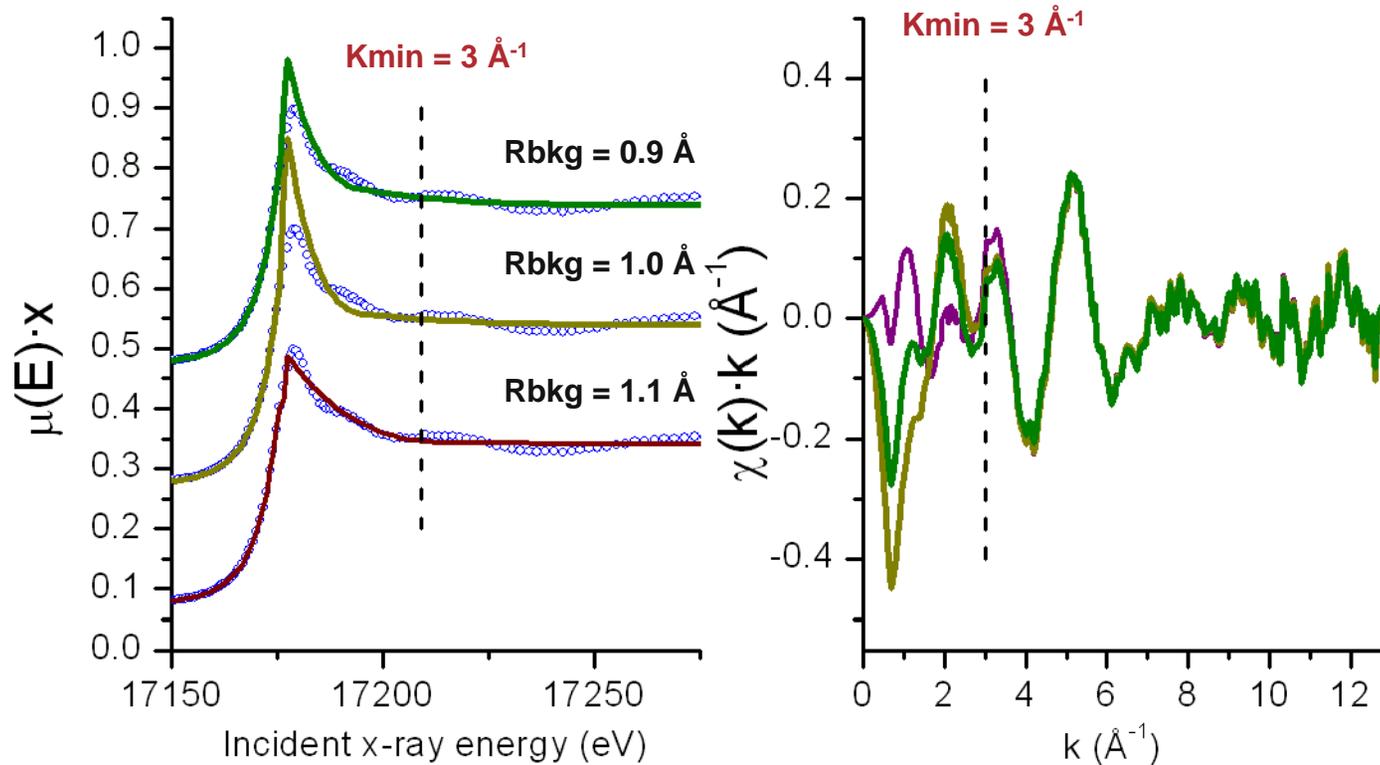


Effect of a large change in Rbkg

- Rbkg: Controls the curvature of the background and is usually set to about half the first nearest neighbor distance.
- Small values for Rbkg (0.5 Å) result in significant signal at low R values, where no neighboring atoms are present.
- Large values for Rbkg (1.5 Å) result in the removal of signal from the first shell signal.



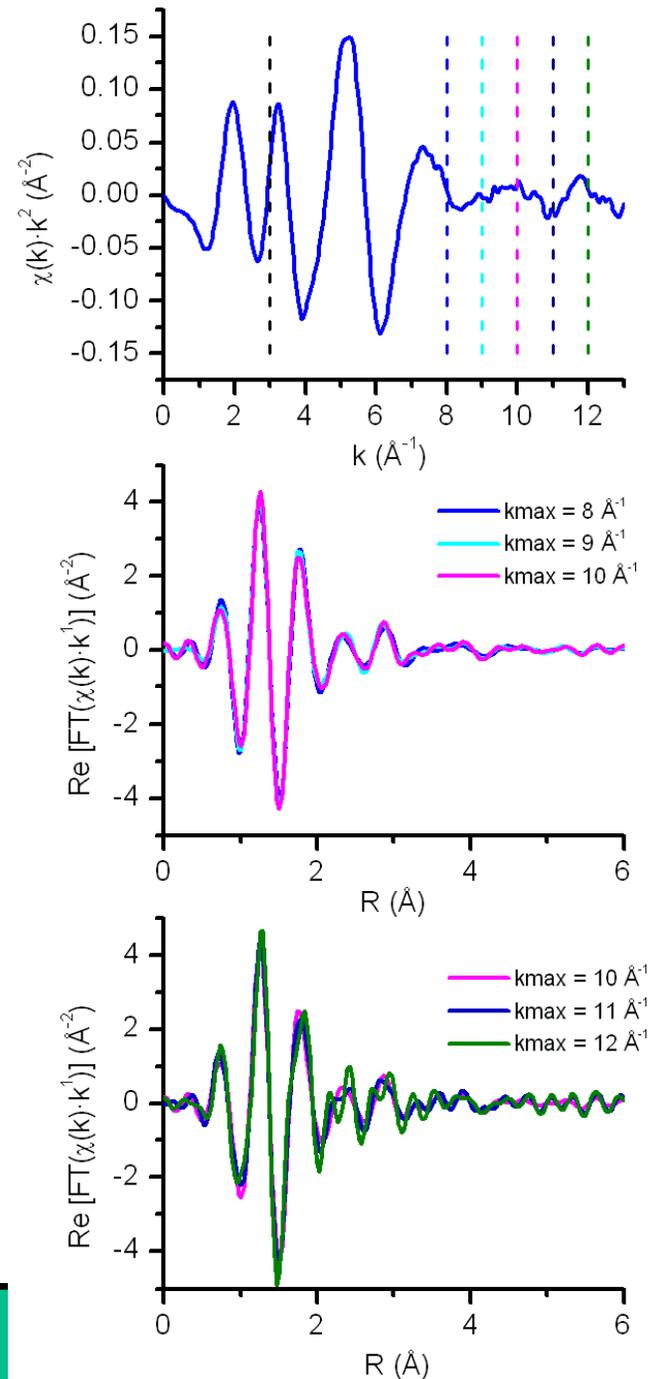
Effect of a small change in Rbkg



- Small changes in Rbkg can be used to determine the minimum k-range to use in the Fourier transform.
- EXAFS signal should not depend on Rbkg.
- K_{min} of 3 \AA^{-1} uses the part of the spectra that does not depend on Rbkg.

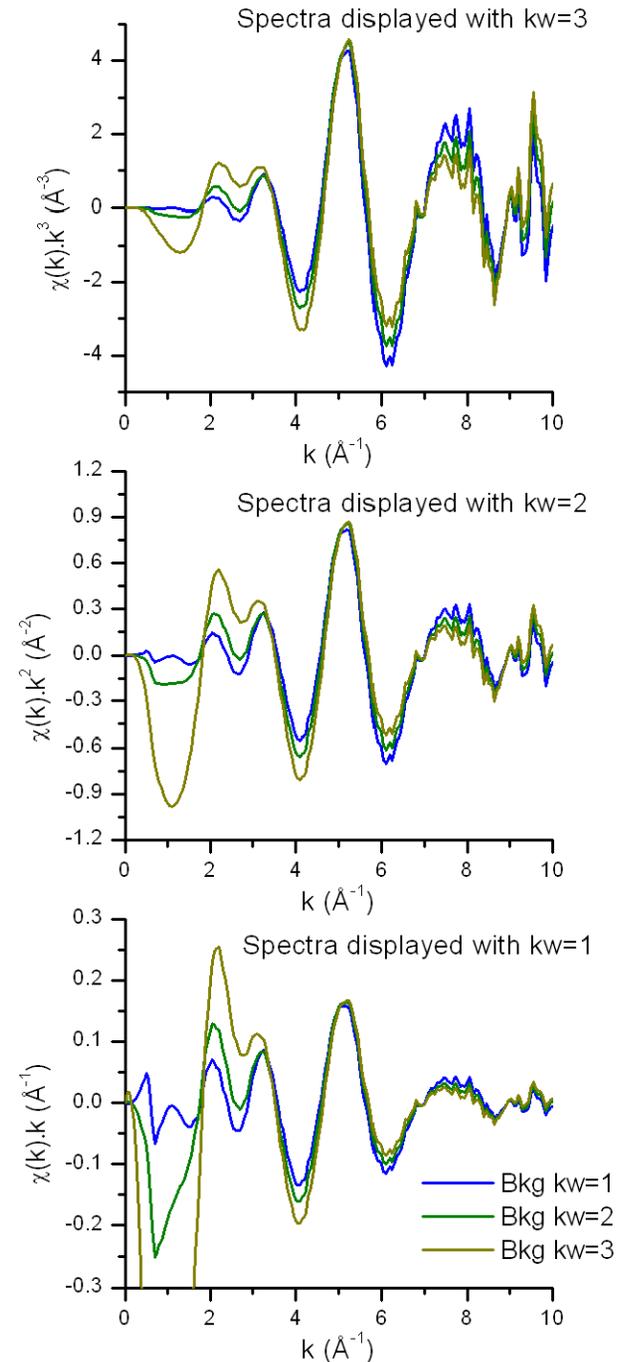
Choosing K_{max} in the Fourier Transform

- Comparison of the Real part of the Fourier transform using incremental values for the maximum k-value (K_{max}) can be used to determine K_{max} .
- The Real part of the Fourier transform will be smooth and similar for the different k_{max} values as long as significant noise is not included in the Fourier transform.
- K_{max} values of 11 \AA^{-1} and 12 \AA^{-1} include some noise in the FT



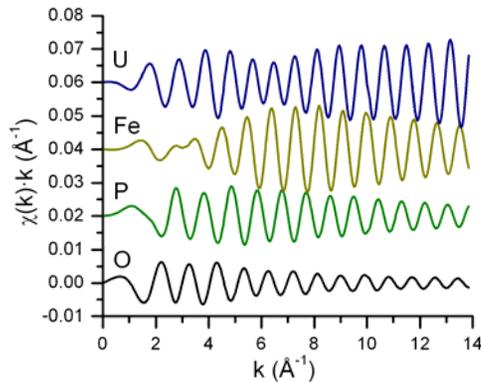
Effect of k-weight in the background removal process

- Background is removed by using a k-weight of 1, 2, or 3.
- Resulting EXAFS signal is displayed using a k-weight of 1, 2, or 3
- Use the background k-weight that results in an evenly weighted EXAFS signal at low k, independent of the k-weight used to display the spectrum

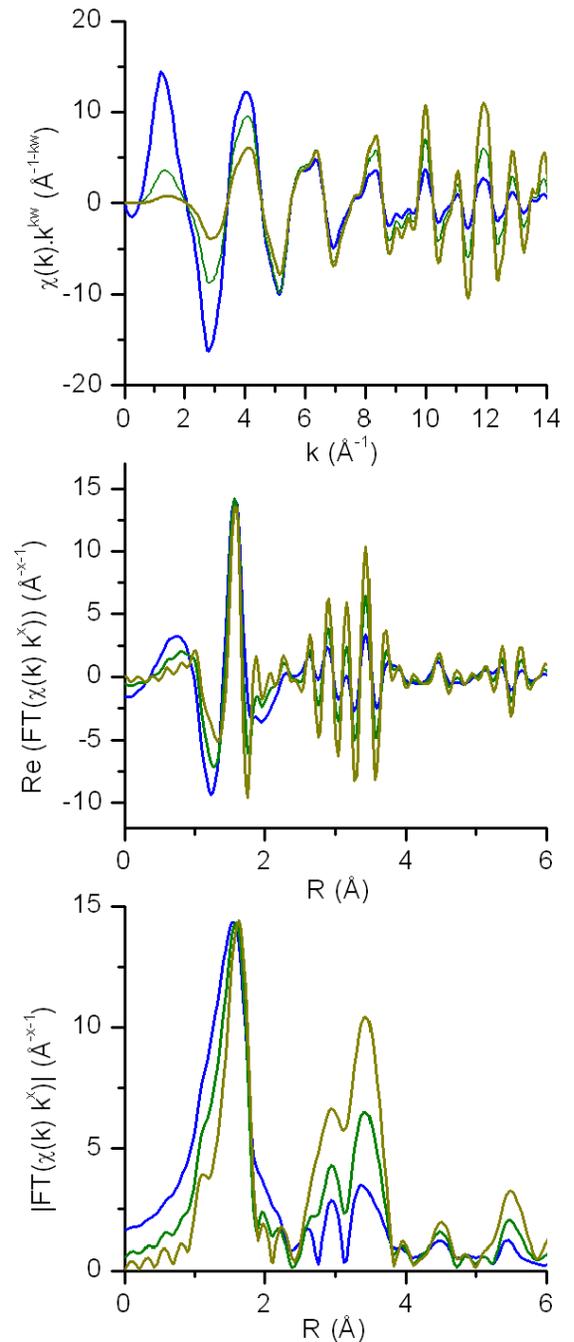


K-weight used in Fourier Transform

EXAFS signal for U-X neighbor at 4 Angstroms



- EXAFS signal is processed with k-weight of 1, 2, and 3 and then rescaled so that the signal is the same height for the first shell in the Fourier transform.
- The signal from 3 to 4 \AA increases with k-weight indicating that there is a atom with stronger signal at higher k-values in this shell
- K-dependence of the EXAFS signal can be used to differentiate neighboring atom types and reduce correlations between EXAFS parameters



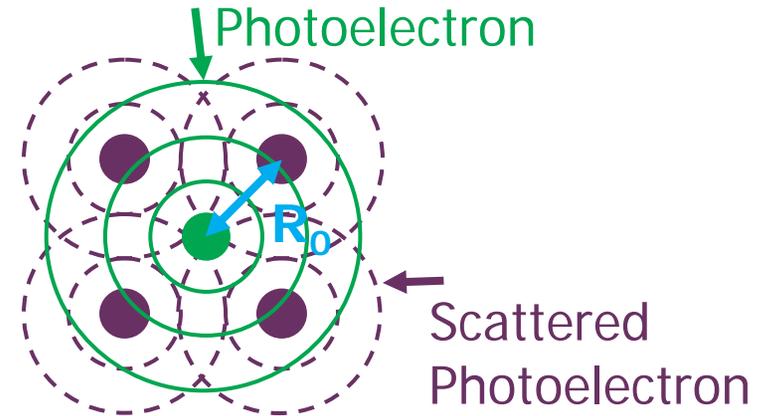
EXAFS Equation

$$\chi(k) = \sum_i \chi_i(k)$$

$$\chi_i(k) \equiv \frac{(N_i S_0^2) F_{eff_i}(k)}{k R_i^2} \sin(2kR_i + \varphi_i(k)) e^{-2\sigma_i^2 k^2} e^{-\frac{2R_i}{\lambda(k)}}$$

$$R_i = R_{0i} + \Delta R_i$$

$$k^2 = \frac{2m_e(E - E_0 + \Delta E_0)}{\hbar}$$



Theoretically calculated values

- $F_i(k)$ effective scattering amplitude
- $\varphi_i(k)$ effective scattering phase shift
- $\lambda(k)$ mean free path

Starting values

- R_0 initial path length

Parameters often determined from a fit to data

- N_i degeneracy of path
- S_0^2 passive electron reduction factor
- σ_i^2 mean squared displacement
- ΔE_0 energy shift
- ΔR change in half-path length